P-Channel Enhancement Mode Power MOSFET

Description

The HM70P04K uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge .This device is well suited for high current load applications.

General Features

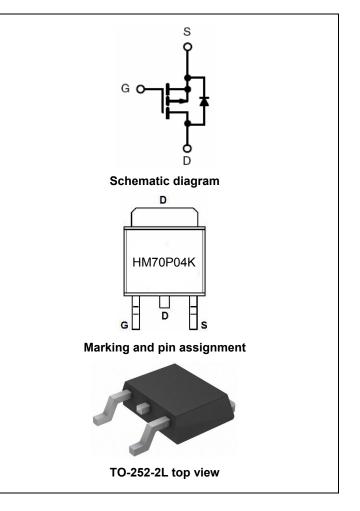
- V_{DS} =-40V, I_{D} =-70A $R_{DS(ON)}$ <10m Ω @ V_{GS} =-10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switch
- Load switch in high current applications
- DC/DC converters

100% UIS TESTED!

100% AVds TESTED!



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM70P04K	HM70P04K	TO-252-2L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-40	V
Gate-Source Voltage	V _G s	±20	V
Drain Current-Continuous	I _D	-70	Α
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	-35	Α
Pulsed Drain Current	I _{DM}	-115	Α
Maximum Power Dissipation	P _D	65	W
Derating factor		0.52	W /℃
Single pulse avalanche energy (Note 5)	E _{AS}	1020	mJ
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 150	$^{\circ}$ C



Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	$R_{ heta JC}$	1.92	°C/W
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Electrical Characteristics (T_C=25°C unless otherwise noted)

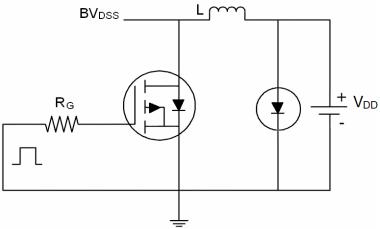
Parameter	Symbol	Symbol Condition		Тур	Max	Unit
Off Characteristics	<u>.</u>					
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA -40		-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-40V,V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V		-	±100	nA
On Characteristics (Note 3)	<u>.</u>					
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=-250\mu A$	-1.2	-1.9	-2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-20A	-	7.5	10	mΩ
Forward Transconductance	g FS	V _{DS} =-10V,I _D =-20A	-	50	-	S
Dynamic Characteristics (Note4)	<u>.</u>					
Input Capacitance	C _{lss}	\/ 00\/\/ 0\/	-	6460	-	PF
Output Capacitance	C _{oss}	V_{DS} =-20V, V_{GS} =0V, F=1.0MHz	-	684	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVITZ	-	600	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	15	-	nS
Turn-on Rise Time	t _r	V_{DD} =-20V, R_L =2 Ω ,	-	12	-	nS
Turn-Off Delay Time	$t_{\sf d(off)}$	V_{GS} =-10 V , R_G =1 Ω	-	70	-	nS
Turn-Off Fall Time	t _f		-	18	-	nS
Total Gate Charge	Qg	V - 20 I - 20 A	-	106		nC
Gate-Source Charge	Q _{gs}	V_{DS} =-20, I_{D} =-20A, V_{GS} =-10V	-	22		nC
Gate-Drain Charge	Q _{gd}	V _{GS} 10V	-	27		nC
Drain-Source Diode Characteristics	·					
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-10A	-		-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-70	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =- 10A	-	53		nS
Reverse Recovery Charge	Qrr	di/dt = -100A/µs(Note3)	-	50		nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

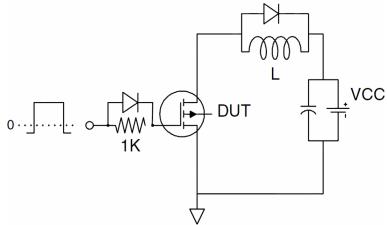
- **1.** Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition: Tj=25 $^{\circ}\text{C}$,V_{DD}=-20V,V_G=-10V,L=1mH,Rg=25 Ω ,I_{AS}=45A

Test Circuit

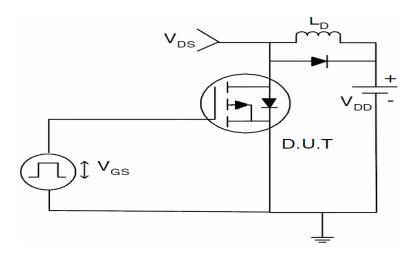
1) E_{AS} Test Circuit

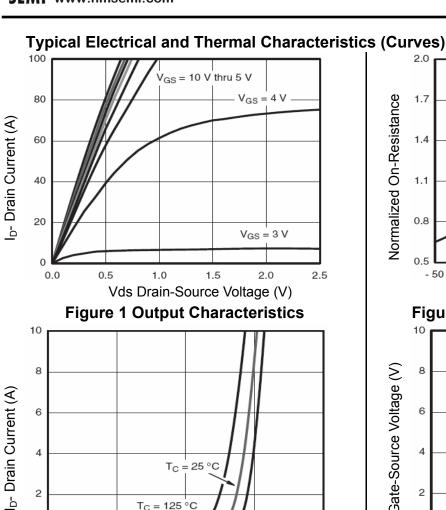


2) Gate Charge Test Circuit



3) Switch Time Test Circuit





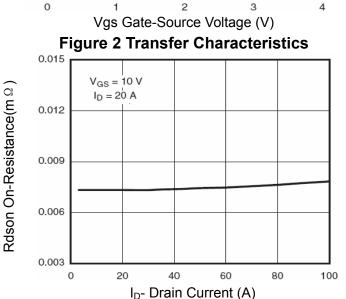


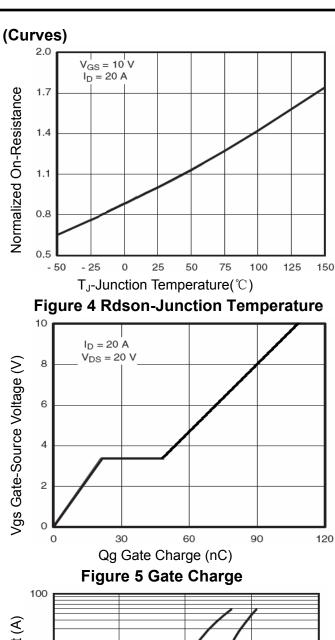
Figure 3 Rdson- Drain Current

T_C = 25 °C

= - 55 °C

T_C = 125 °C

0



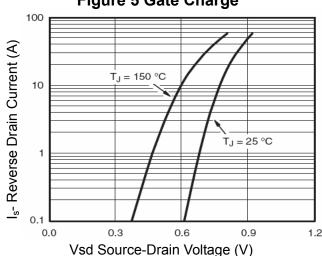
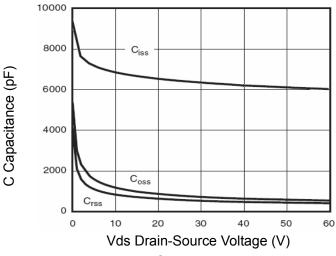


Figure 6 Source- Drain Diode Forward



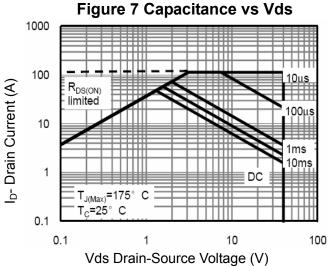


Figure 8 Safe Operation Area

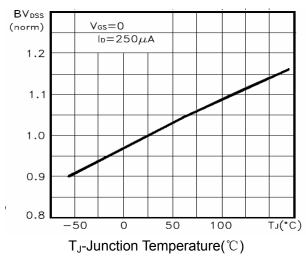


Figure 9 BV_{DSS} vs Junction Temperature

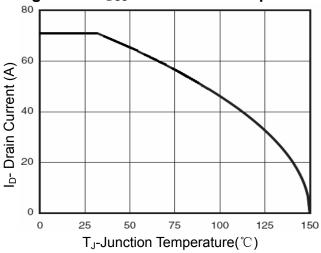


Figure 10 ID Current Derating vs Junction Temperature

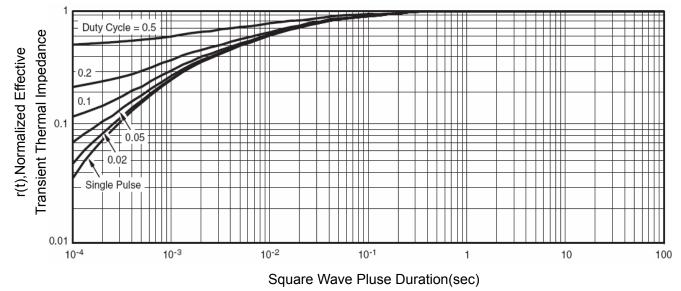
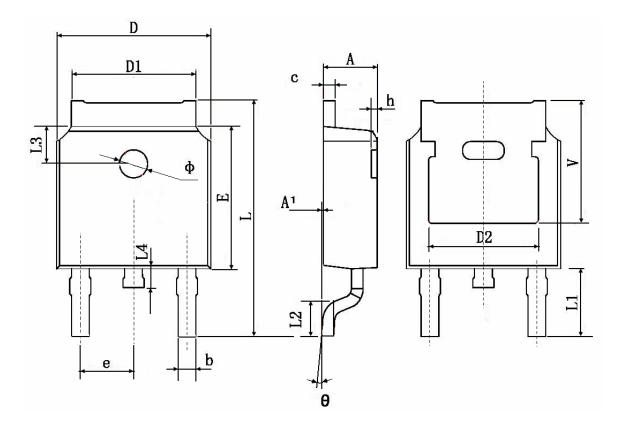


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-252 Package Information



Symbol	Dimensions I	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483	TYP.	0.190 TYP.		
Е	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	TYP.	0.211 TYP.		

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